

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/670,747	YEH ET AL.	
		Examiner	Art Unit	Page 1 of 1
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,356,622 B1	03-2002	Hassell et al.	379/1.01
	B	US-5,796,742	08-1998	Klotzbach et al.	370/466
	C	US-6,618,377 B1	09-2003	Miriyalu, Prasad	370/395.1
	D	US-5,907,610	05-1999	Onweller, Arthur E.	379/242
	E	US-			
	F	US-			
	G	US-			
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	L	US-			
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B	US-6,366,561	04-2002	Bender, Paul E.	370/238
C	US-6,640,314	10-2003	Lelaure et al.	714/11
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